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Application No. <u>10053106</u>	Prepared by <u>cwc</u>	Tracking Number <u>05873169</u>	
Examiner-GAU <u>Font</u>	Date <u>1-7-04</u>	Week Date <u>12-08-03</u>	
<u>2877</u>	No. of queries <u>- 2 -</u>	<u>IFW</u>	

JACKET			
a. Serial No.	f. Foreign Priority	k. Print Claim(s)	p. PTO-1449
b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	<u>r. Abstract</u>
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other

SPECIFICATION	MESSAGE
a. Page Missing	<u>Please provide</u>
b. Text Continuity	<u>- claims</u>
c. Holes through Data	<u>- Abstract</u>
d. Other Missing Text	
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i. Appendix	<u>Thank you</u>
j. Amendments	
k. Other	
CLAIMS	
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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-132001	Application No. 10/053,106
Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Peter de Groot et al.	
		Filing Date November 2, 2001	Group Art Unit

U.S. Patent Documents

Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	6,195,168 B1	02/2001	De Lega et al.	356	497	
	AB	5,398,113	03/1995	de Groot	356	360	
	AC						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AD							
	AE							
	AF							
	AG							
	AH							

Other Documents (Include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AI	P. de Groot and Leslie Deck, "Surface profiling by analysis of white-light interferograms in the spatial frequency domain," J. Mod. Opt. 42(2), 389-401 (1995).
	AJ	T. Dresel, G. Hausler and H. Venzke, "Three-dimensional sensing of rough surfaces by coherence radar," Appl. Opt. 31(7), 919-925 (1992).
	AK	Gordon S. Kino and Stanley S. C. Chim, "Mirau correlation microscope," Appl. Opt. 29(26), 3775-3783 (1990).
	AL	A. Harasaki and J. C. Wyant, "Fringe modulation skewing effect in white-light vertical scanning interferometry," Appl. Opt. 39(13), 2101-2108 (2000).
	AM	L. Deck and P. de Groot, "High-speed non-contact profiler based on scanning white light interferometry," Appl. Opt. 33(31), 7334-7338 (November 1, 1994).

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	